

Microstructures and electronic characters of β -Ga₂O₃ on different substrates: Exploring the role of surface chemistry and structure

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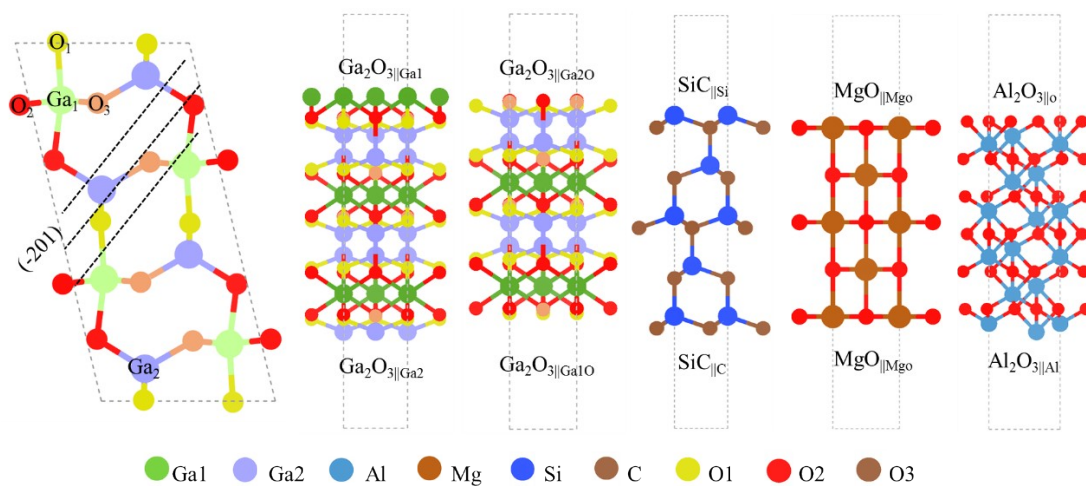


Figure S1. Side views of β -Ga₂O₃, and β -Ga₂O₃ (-201) surfaces, SiC (0001) surfaces, MgO (001) surfaces, Al₂O₃ (001) surfaces with different terminations.

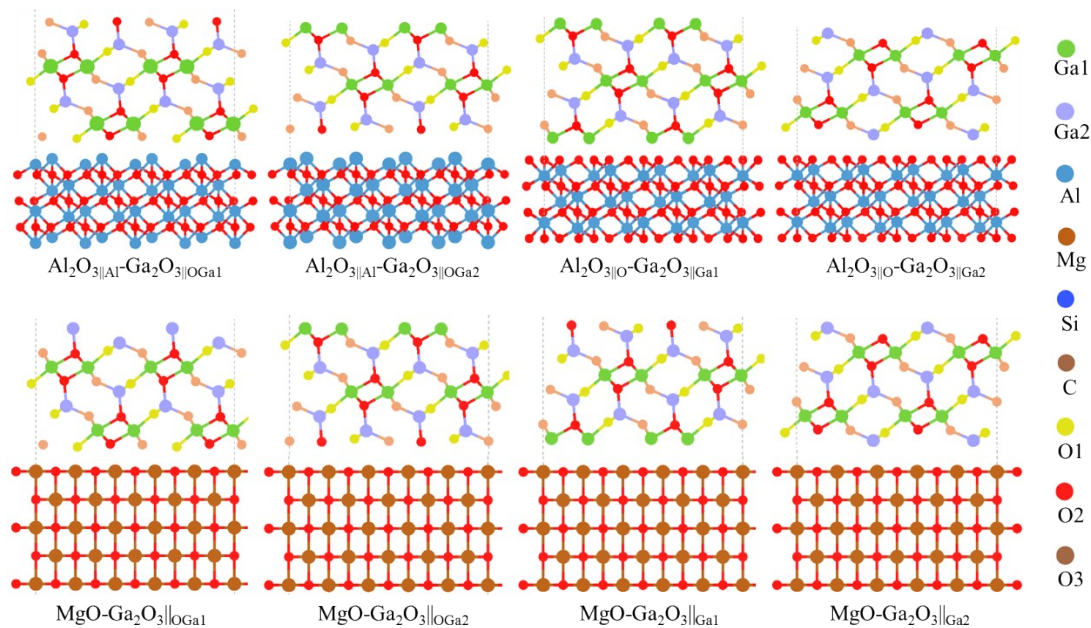


Figure S2. Side views of $\text{Al}_2\text{O}_3\text{-Ga}_2\text{O}_3$ and $\text{MgO-Ga}_2\text{O}_3$ interfaces with different terminations.

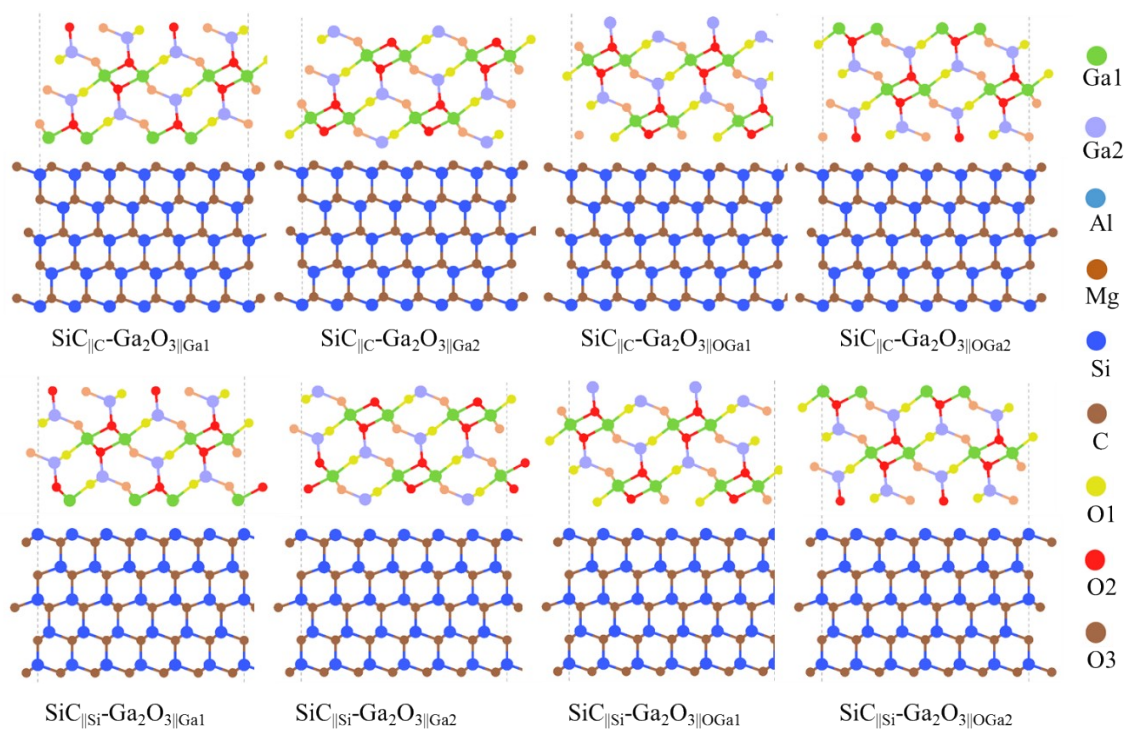


Figure S3. Side views of $\text{SiC-Ga}_2\text{O}_3$ interfaces with different terminations.

Table S1. The lattice strain along a and b direction and the average lattice strain of β -Ga₂O₃ in these different Al₂O₃-Ga₂O₃, MgO-Ga₂O₃, and SiC-Ga₂O₃ interfaces. The difference of dangling bonds between Ga₂O₃ and substrate part in these substrate-Ga₂O₃ interfaces with different terminations.

Interface	Strain (%)			Dangling bonds
	a direction	b direction	average	
Al ₂ O ₃ _{Al} -Ga ₂ O ₃ _{OGa1}	10.35	2.55	4.3	2
Al ₂ O ₃ _{Al} -Ga ₂ O ₃ _{OGa2}	10.35	2.55	4.3	1
Al ₂ O ₃ _O -Ga ₂ O ₃ _{Ga1}	10.35	2.55	4.3	12
Al ₂ O ₃ _O -Ga ₂ O ₃ _{Ga2}	10.35	2.55	4.3	12
MgO-Ga ₂ O ₃ _{OGa1}	-0.34	-3.75	-1.36	8
MgO-Ga ₂ O ₃ _{OGa2}	-0.34	-3.75	-1.36	8
MgO-Ga ₂ O ₃ _{Ga1}	-0.34	-3.75	-1.36	2
MgO-Ga ₂ O ₃ _{Ga2}	-0.34	-3.75	-1.36	5
SiC _C -Ga ₂ O ₃ _{OGa1}	5.73	-1.29	2.52	0
SiC _C -Ga ₂ O ₃ _{OGa2}	5.73	-1.29	2.52	0
SiC _C -Ga ₂ O ₃ _{Ga1}	5.73	-1.29	2.52	2
SiC _C -Ga ₂ O ₃ _{Ga2}	5.73	-1.29	2.52	4
SiC _{Si} -Ga ₂ O ₃ _{OGa1}	5.73	-1.29	2.52	0
SiC _{Si} -Ga ₂ O ₃ _{OGa2}	5.73	-1.29	2.52	0
SiC _{Si} -Ga ₂ O ₃ _{Ga1}	5.73	-1.29	2.52	2
SiC _{Si} -Ga ₂ O ₃ _{Ga2}	5.73	-1.29	2.52	4

Table S2. The valence band offset (VBO) and conduction band offset (CBO) coupling with the band gap of Ga₂O₃ part in these different Al₂O₃-Ga₂O₃, MgO-Ga₂O₃, and SiC-Ga₂O₃ interfaces.

Interface	VBO (eV)	CBO (eV)	Gap (eV)	Band alignment
Al ₂ O ₃ _O -Ga ₂ O ₃ _{Ga2}	0.02	0.45	2.60	Type-II
Al ₂ O ₃ _O -Ga ₂ O ₃ _{Ga1}	0.10	0.23	2.82	Type-II
Al ₂ O ₃ _{Al} -Ga ₂ O ₃ _{OGa2}	0.12	0.50	3.30	Type-II
Al ₂ O ₃ _{Al} -Ga ₂ O ₃ _{OGa1}	0.25	0.94	2.70	Type-II
MgO-Ga ₂ O ₃ _{Ga2}	0.12	0.22	3.42	Type-I
MgO-Ga ₂ O ₃ _{Ga1}	0.65	0.31	2.79	Type-I
MgO-Ga ₂ O ₃ _{OGa2}	0.15	0.58	3.42	Type-I
MgO-Ga ₂ O ₃ _{OGa1}	0.25	0.56	3.18	Type-I
SiC _{Si} -Ga ₂ O ₃ _{Ga2}	0.39	0.07	2.43	Type-II
SiC _{Si} -Ga ₂ O ₃ _{Ga1}	0.45	0.11	2.43	Type-II
SiC _{Si} -Ga ₂ O ₃ _{OGa2}	0.06	0.27	3.35	Type-I
SiC _{Si} -Ga ₂ O ₃ _{OGa1}	0.02	0.42	3.22	Type-I
SiC _C -Ga ₂ O ₃ _{Ga2}	0.61	0.09	2.75	Type-II
SiC _C -Ga ₂ O ₃ _{Ga1}	0.39	0.23	2.68	Type-II
SiC _C -Ga ₂ O ₃ _{OGa2}	0.12	0.29	3.05	Type-I
SiC _C -Ga ₂ O ₃ _{OGa1}	0.08	0.42	2.98	Type-I